IGBT - Field Stop II

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop II Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss. The IGBT is well suited for UPS and solar applications. Incorporated into the device is a soft and fast co–packaged free wheeling diode with a low forward voltage.

Features

- Extremely Efficient Trench with Field Stop Technology
- $T_{Jmax} = 175^{\circ}C$
- Soft Fast Reverse Recovery Diode
- Optimized for High Speed Switching
- 10 us Short Circuit Capability
- These are Pb-Free Devices

Typical Applications

- Solar Inverter
- Uninterruptible Power Inverter Supplies (UPS)
- Welding

ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-emitter voltage	V_{CES}	1200	V
Collector current @ Tc = 25°C @ Tc = 100°C	I _C	30 15	A
Pulsed collector current, T _{pulse} limited by T _{Jmax}	I _{CM}	60	Α
Diode forward current @ Tc = 25°C @ Tc = 100°C	I _F	30 15	А
Diode pulsed current, T _{pulse} limited by T _{Jmax}	I _{FM}	60	Α
Gate-emitter voltage Transient gate-emitter voltage $(T_{pulse} = 5 \mu s, D < 0.10)$	$V_{\sf GE}$	±20 ±30	V
Power Dissipation @ Tc = 25°C @ Tc = 100°C	P _D	294 147	W
Short Circuit Withstand Time V _{GE} = 15 V, V _{CE} = 500 V, T _J ≤ 150°C	T _{SC}	10	μS
Operating junction temperature range	TJ	-55 to +175	°C
Storage temperature range	T _{stg}	-55 to +175	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T _{SLD}	260	°C

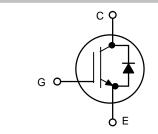
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

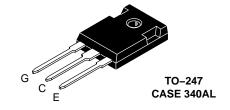


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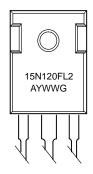
http://onsemi.com

15 A, 1200 V V_{CEsat} = 2.0 V E_{off} = 0.37 mJ





MARKING DIAGRAM



A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping
NGTB15N120FL2WG	TO-247 (Pb-Free)	30 Units / Rail

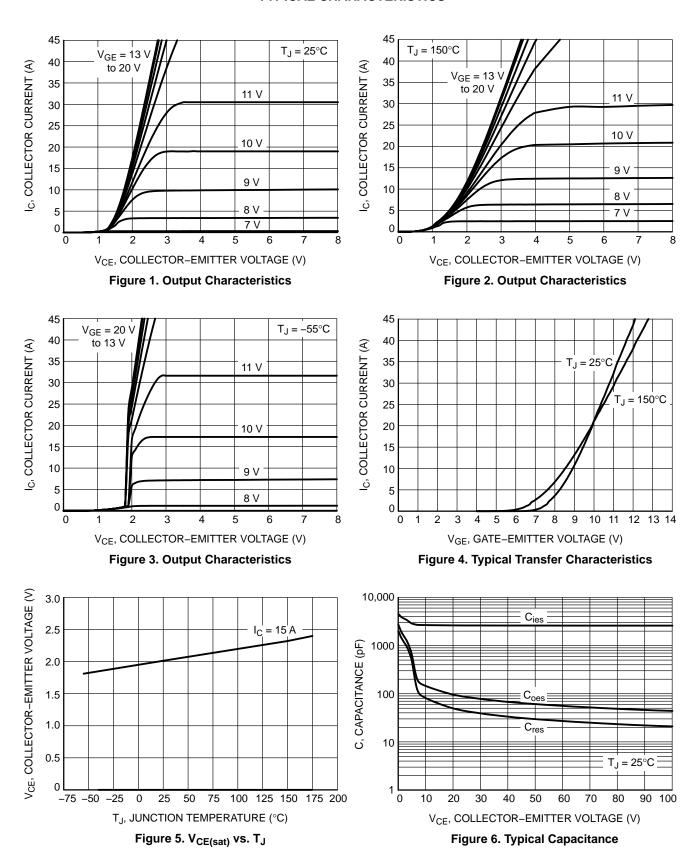
THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction–to–case, for IGBT	$R_{\theta JC}$	0.51	°C/W
Thermal resistance junction-to-case, for Diode		0.81	°C/W
Thermal resistance junction–to–ambient		40	°C/W

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC	•					
Collector–emitter breakdown voltage, gate–emitter short–circuited	$V_{GE} = 0 \text{ V}, I_{C} = 500 \mu\text{A}$	V _{(BR)CES}	1200	_	_	V
Collector–emitter saturation voltage	V _{GE} = 15 V, I _C = 15 A V _{GE} = 15 V, I _C = 15 A, T _J = 175°C	V _{CEsat}		2.00 2.40	2.40 -	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_{C} = 400 \mu A$	$V_{GE(th)}$	4.5	5.65	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	V _{GE} = 0 V, V _{CE} = 1200 V V _{GE} = 0 V, V _{CE} = 1200 V, T _J = 175°C	I _{CES}	- -	_ _	0.4 4.0	mA
Gate leakage current, collector–emitter short–circuited	V _{GE} = 20 V , V _{CE} = 0 V	I _{GES}	ı	_	200	nA
Input capacitance		C _{ies}	_	2640	_	pF
Output capacitance	$V_{CE} = 20 \text{ V}, V_{GE} = 0 \text{ V}, f = 1 \text{ MHz}$	C _{oes}	_	88	-	
Reverse transfer capacitance		C _{res}	_	50	_	
Gate charge total		Qg	_	109	_	nC
Gate to emitter charge	$V_{CE} = 600 \text{ V}, I_{C} = 15 \text{ A}, V_{GE} = 15 \text{ V}$	Q _{ge}	_	23	_	
Gate to collector charge		Q _{gc}	-	51	_	
SWITCHING CHARACTERISTIC, INDUC	TIVE LOAD					
Turn-on delay time		t _{d(on)}	_	64	_	ns
Rise time		t _r	_	104	_	
Turn-off delay time	T _J = 25°C	t _{d(off)}	_	132	_	
Fall time	$V_{CC} = 600 \text{ V, } I_{C} = 15 \text{ A}$ $R_{\alpha} = 10 \Omega$	t _f	-	173	-	
Turn-on switching loss	$R_g = 10 \Omega$ $V_{GE} = 0 \text{ V/ } 15 \text{ V}$	E _{on}	-	1.20	-	mJ
Turn-off switching loss		E _{off}	ı	0.37	_	
Total switching loss		E _{ts}	-	1.57	_	
Turn-on delay time		t _{d(on)}	1	62	_	ns
Rise time		t _r	1	126	_	
Turn-off delay time	T _J = 150°C	t _{d(off)}	1	138	_	
Fall time	$V_{CC} = 600 \text{ V}, I_{C} = 15 \text{ A}$ $R_{g} = 10 \Omega$	t _f	-	300	_	
Turn-on switching loss	$R_g = 10 \Omega$ $V_{GE} = 0 \text{ V/ } 15 \text{ V}$	E _{on}	1	1.45	_	mJ
Turn-off switching loss		E _{off}	-	0.76	_	
Total switching loss		E _{ts}	_	2.21	_	
DIODE CHARACTERISTIC						
Forward voltage	$V_{GE} = 0 \text{ V, } I_F = 15 \text{ A}$ $V_{GE} = 0 \text{ V, } I_F = 50 \text{ A, } T_J = 175^{\circ}\text{C}$	V _F	1 1	2.00 2.30	2.60 -	V
Reverse recovery time	$T_J = 25^{\circ}C$	t _{rr}	ı	110	_	ns
Reverse recovery charge	$I_F = 15 \text{Å}, V_R = 200 \text{V}$ $di_F/dt = 200 \text{A/}\mu\text{s}$	Q _{rr}	ı	0.69	_	μC
Reverse recovery current		I _{rrm}	_	11	_	Α

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



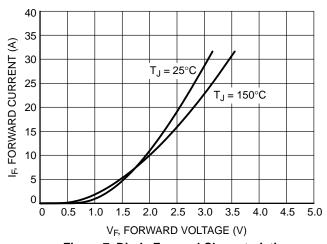


Figure 7. Diode Forward Characteristics

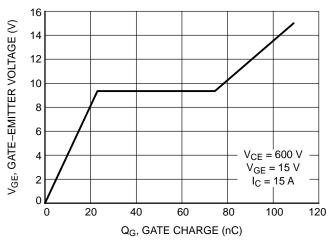


Figure 8. Typical Gate Charge

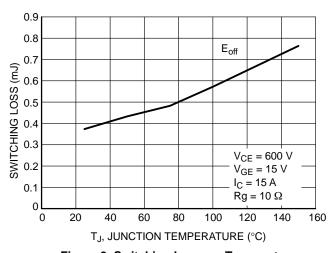


Figure 9. Switching Loss vs. Temperature

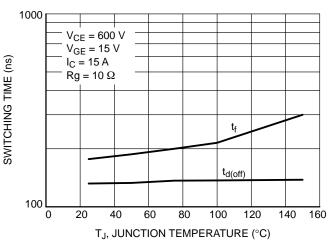


Figure 10. Switching Time vs. Temperature

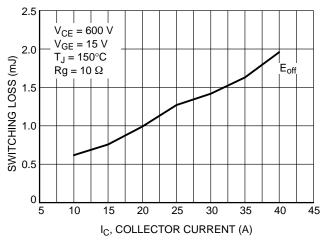


Figure 11. Switching Loss vs. I_C

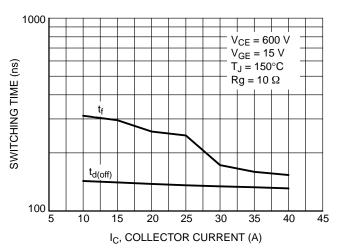


Figure 12. Switching Time vs. I_C

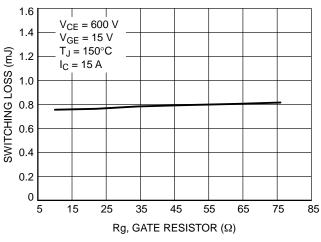


Figure 13. Switching Loss vs. Rg

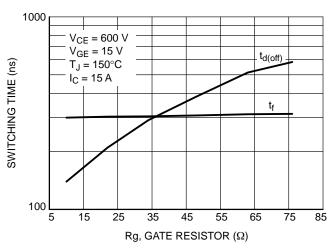


Figure 14. Switching Time vs. Rg

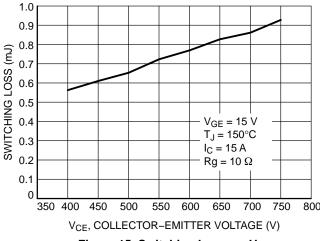


Figure 15. Switching Loss vs. V_{CE}

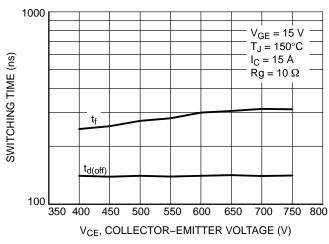


Figure 16. Switching Time vs. V_{CE}

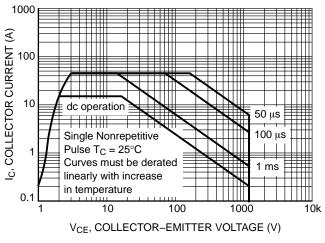


Figure 17. Safe Operating Area

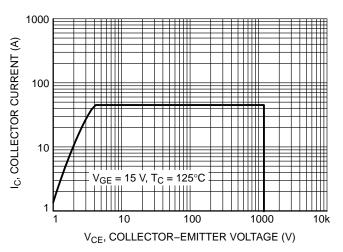


Figure 18. Reverse Bias Safe Operating Area

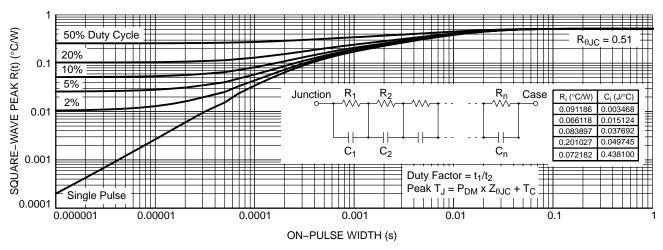


Figure 19. IGBT Die Self-heating Square-wave Duty Cycle Transient Thermal Response

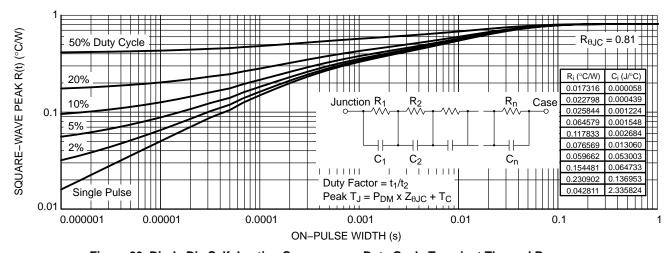
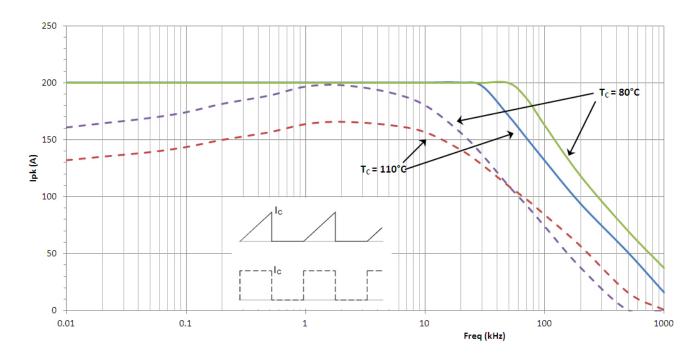


Figure 20. Diode Die Self-heating Square-wave Duty Cycle Transient Thermal Response



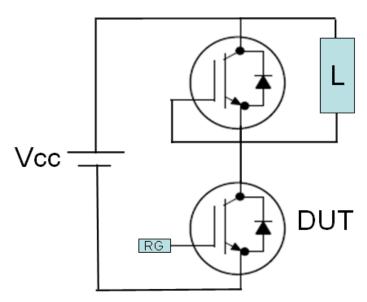


Figure 21. Test Circuit for Switching Characteristics

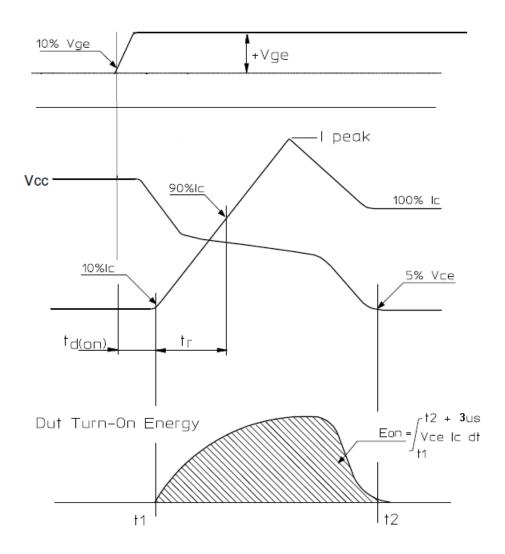


Figure 22. Definition of Turn On Waveform

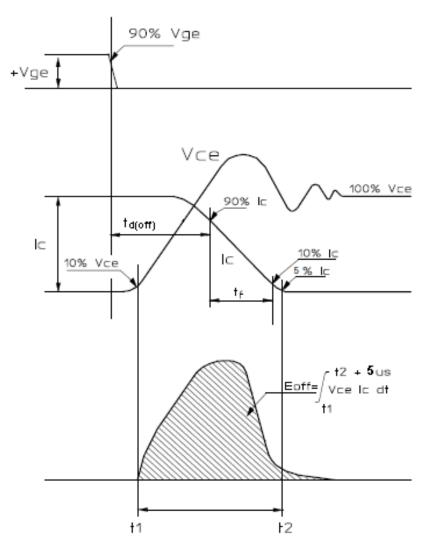
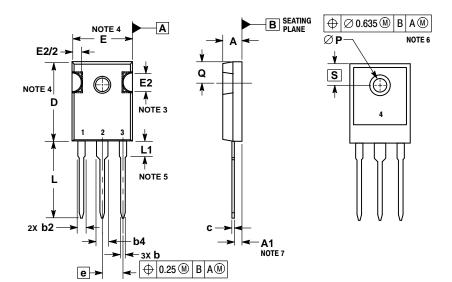


Figure 23. Definition of Turn Off Waveform

PACKAGE DIMENSIONS

TO-247 CASE 340AL **ISSUE A**



NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.

- SLOT REQUIRED, NOTCH MAY BE ROUNDED.
 DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREME OF THE PLASTIC BODY.
 LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY
- L1.

 ØP SHALL HAVE A MAXIMUM DRAFT ANGLE OF 1.5° TO THE
- TOP OF THE PART WITH A MAXIMUM DIAMETER OF 3.91.

 DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED

	MILLIMETERS			
DIM	MIN	MAX		
Α	4.70	5.30		
A1	2.20	2.60		
b	1.00	1.40		
b2	1.65	2.35		
b4	2.60	3.40		
С	0.40	0.80		
D	20.30	21.40		
E	15.50	16.25		
E2	4.32	5.49		
е	5.45	5.45 BSC		
L	19.80	20.80		
L1	3.50	4.50		
P	3.55	3.65		
Q	5.40	6.20		
S	6.15 BSC			

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